

课程大纲

COURSE SYLLABUS

1.	课程代码/名称 Course Code/Title	现代物理实验 Modern Physics Experiments																
2.	课程性质 Compulsory/Elective	专业选修课 Major Elective Courses																
3.	课程学分/学时 Course Credit/Hours	2/48 (16 理论 lecture + 32 实验 lab project)																
4.	授课语言 Teaching Language	Chinese 中文																
5.	授课教师 Instructor(s)	崔德虎 Cui Dehu																
6.	先修要求 Pre-requisites	集成电路工艺实践 Silicon VLSI Technology, Fundamentals, Practice and Modelling																
7.	教学目标 Course Objectives	<p>课程为博士研究生专业核心课。通过该门课程的学习，学生们可学习集成电路的工艺、表征等知识，并能熟练使用集成电路工艺所使用的基本仪器，达到理论与实践相结合的目的。课程考核方式为课程报告 50%，课程实验 50%。讲授 16 学时，实验 32 学时。</p> <p>This lecture focuses on the basic features of the silicon integrated circuits manufacture, including their distinctions and common underlying principle. Such as: CMOS Technology, lithography, etching, various deposition techniques, vacuum technology, evaporation, ion implantation, epitaxy, chemical vapour deposition, plasma, film analysis.</p>																
8.	教学方法 Teaching Methods	讲授 Lectures, 习题/辅导/讨论 Tutorials, 实验项目 Lab Project																
9.	教学内容 Course Contents	<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 20%;">Section 1 (2 hours)</td> <td>晶体生长：晶圆片制造与硅晶圆片的基本特性，圆片的准备和规格 Crystal Growth, Wafer fabrication and basic properties of silicon wafer</td> </tr> <tr> <td>Section 2 (2 hours)</td> <td>半导体制造——洁净室、晶圆片清洗与吸杂处理 Semiconductor manufacturing, clean rooms, wafer cleaning and guttering;</td> </tr> <tr> <td>Section 3 (2 hours)</td> <td>光刻 Lithography;</td> </tr> <tr> <td>Section 4 (2 hours)</td> <td>热氧化和 Si-SiO₂ 界面 Thermal oxidation and Si/SiO₂ interface</td> </tr> <tr> <td>Section 5 (2 hours)</td> <td>扩散，离子注入； Dopant diffusion; Ion implantation;</td> </tr> <tr> <td>Section 6 (2 hours)</td> <td>薄膜淀积； Thin film deposition</td> </tr> <tr> <td>Section 7 (2 hours)</td> <td>刻蚀 Etching;</td> </tr> <tr> <td>Section 8 (2 hours)</td> <td>后端工艺 Back-end technology</td> </tr> </table>	Section 1 (2 hours)	晶体生长：晶圆片制造与硅晶圆片的基本特性，圆片的准备和规格 Crystal Growth, Wafer fabrication and basic properties of silicon wafer	Section 2 (2 hours)	半导体制造——洁净室、晶圆片清洗与吸杂处理 Semiconductor manufacturing, clean rooms, wafer cleaning and guttering;	Section 3 (2 hours)	光刻 Lithography;	Section 4 (2 hours)	热氧化和 Si-SiO ₂ 界面 Thermal oxidation and Si/SiO ₂ interface	Section 5 (2 hours)	扩散，离子注入； Dopant diffusion; Ion implantation;	Section 6 (2 hours)	薄膜淀积； Thin film deposition	Section 7 (2 hours)	刻蚀 Etching;	Section 8 (2 hours)	后端工艺 Back-end technology
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	Lab Project (32 hours)	<p>要求学生掌握电子器件的基本实验步骤.</p> <p>Students should master the fundamental principles of electronic materials and devices.</p>						
10.	课程考核 Course Assessment							
	<p>①考试；②分数构成。</p> <table border="0" data-bbox="220 539 957 658"> <tr> <td>出勤及课堂表现 Attendance and class performance</td> <td>10%</td> </tr> <tr> <td>期末考试 Final exam</td> <td>40%</td> </tr> <tr> <td>课程项目及报告 Project and presentation</td> <td>50%</td> </tr> </table>		出勤及课堂表现 Attendance and class performance	10%	期末考试 Final exam	40%	课程项目及报告 Project and presentation	50%
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11.	教材及其它参考资料 Textbook and Supplementary Readings							
	<p>Silicon VLSI Technology, Fundamentals, Practice and Modelling</p> <p>超大规模集成电路工艺技术：理论，实践及模型。</p>							